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# HM511000A Series HM511000AL Series

Jameco Part Number 42219

1048576-Word x 1-Bit CMOS Dynamic RAM

## DESCRIPTION

The Hitachi HM511000A/AL series is a CMOS dynamic RAM organized 1048576-word x 1-bit. HM511000A/AL has realized higher density, higher performance and various functions by employing 1.3  $\mu\text{m}$  CMOS process technology and some new CMOS circuit design technologies.

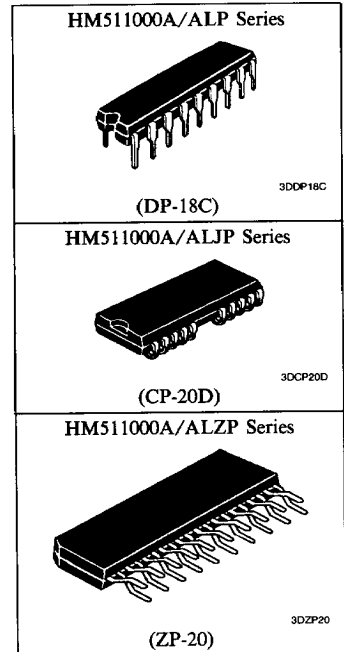
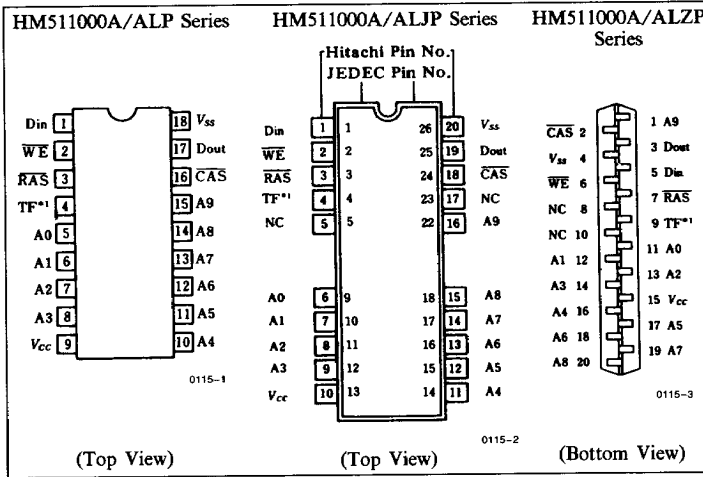
The HM511000A/AL offers Fast Page Mode as a high speed access mode.

Multiplexed address input permits the HM511000A/AL to be packaged in standard 18-pin plastic DIP, 20-pin plastic ZIP and 20-pin plastic SOJ.

## FEATURES

- High Speed  
Access Time ..... 60 ns/70 ns/80 ns/100 ns/120 ns (max)
- Low Power Dissipation  
Active Mode ..... 495 mW/440 mW/385 mW/330 mW/275 mW (max)  
Standby Mode ..... 11 mW (max)
- Single 5V Supply ( $\pm 10\%$ )
- Fast Page Mode Capability
- 512 Refresh Cycles ..... (8 ms)
- 2 Variations of Refresh  
RAS Only Refresh  
CAS Before RAS Refresh

## PIN OUT



## PIN DESCRIPTION

Pin Name	Function
A <sub>0</sub> -A <sub>9</sub>	Address Input
A <sub>0</sub> -A <sub>8</sub>	Refresh Address Input
D <sub>in</sub>	Data-in
D <sub>out</sub>	Data-out
RAS	Row Address Strobe
CAS	Column Address Strobe
WE	Read/Write Input
TF <sup>1</sup>	Test Function
V <sub>CC</sub>	Power (+ 5V)
V <sub>SS</sub>	Ground

Note: 1. TF pin can be connected with any line or unconnected provided the voltage level of TF pin must be kept lower than V<sub>CC</sub> + 0.5V.

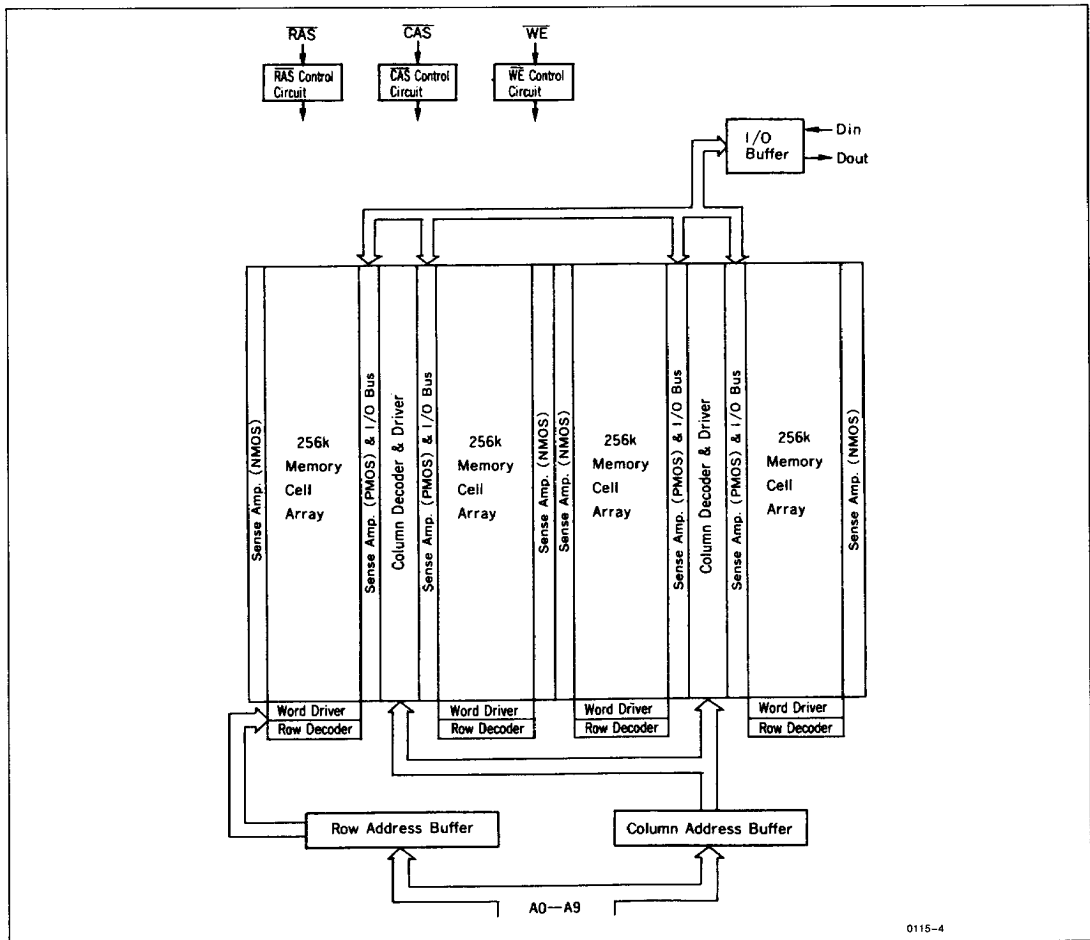


■ ORDERING INFORMATION

Part No.	Access Time	Package
HM511000AP-6	60 ns	300 mil 18-pin Plastic DIP (DP-18C)
HM511000AP-7	70 ns	
HM511000AP-8	80 ns	
HM511000AP-10	100 ns	
HM511000AP-12	120 ns	
HM511000AJP-6	60 ns	300 mil 20-pin Plastic SOJ (CP-20D)
HM511000AJP-7	70 ns	
HM511000AJP-8	80 ns	
HM511000AJP-10	100 ns	
HM511000AJP-12	120 ns	
HM511000AZP-6	60 ns	400 mil 20-pin Plastic ZIP (ZP-20)
HM511000AZP-7	70 ns	
HM511000AZP-8	80 ns	
HM511000AZP-10	100 ns	
HM511000AZP-12	120 ns	

Part No.	Access Time	Package
HM511000ALP-6	60 ns	300 mil 18-pin Plastic DIP (DP-18C)
HM511000ALP-7	70 ns	
HM511000ALP-8	80 ns	
HM511000ALP-10	100 ns	
HM511000ALP-12	120 ns	
HM511000ALJP-6	60 ns	300 mil 20-pin Plastic SOJ (CP-20D)
HM511000ALJP-7	70 ns	
HM511000ALJP-8	80 ns	
HM511000ALJP-10	100 ns	
HM511000ALJP-12	120 ns	
HM511000ALZP-6	60 ns	400 mil 20-pin Plastic ZIP (ZP-20)
HM511000ALZP-7	70 ns	
HM511000ALZP-8	80 ns	
HM511000ALZP-10	100 ns	
HM511000ALZP-12	120 ns	

■ BLOCK DIAGRAM



0115-4



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■ ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Voltage on Any Pin Relative to V <sub>SS</sub>	V <sub>T</sub>	-1.0 to +7.0	V
Supply Voltage Relative to V <sub>SS</sub>	V <sub>CC</sub>	-1.0 to +7.0	V
Short Circuit Output Current	I <sub>out</sub>	50	mA
Power Dissipation	P <sub>T</sub>	1.0	W
Operating Temperature	T <sub>opr</sub>	0 to +70	°C
Storage Temperature	T <sub>stg</sub>	-55 to +125	°C

■ ELECTRICAL CHARACTERISTICS

• Recommended DC Operating Conditions (T<sub>A</sub> = 0 to +70°C)

Parameter	Symbol	Min	Typ	Max	Unit
Supply Voltage	V <sub>CC</sub>	4.5	5.0	5.5	V
Input High Voltage	V <sub>IH</sub>	2.4	—	6.5	V
Input Low Voltage	V <sub>IL</sub>	-2.0	—	0.8	V

Note: All voltages referenced to V<sub>SS</sub>.

• DC Electrical Characteristics (V<sub>CC</sub> = 5V ± 10%, V<sub>SS</sub> = 0V, T<sub>A</sub> = 0 to +70°C)

Parameter	Symbol	HM511000A /AL-6		HM511000A /AL-7		HM511000 /A-8		HM511000 /A-10		HM511000 /A-12		Unit	Test Conditions	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max			
Operating Current	I <sub>CC1</sub>	—	90	—	80	—	70	—	60	—	50	mA	RAS, CAS Cycling, t <sub>RC</sub> = Min	1, 2
Standby Current	I <sub>CC2</sub>	—	2	—	2	—	2	—	2	—	2	mA	TTL Interface RAS, CAS = V <sub>IH</sub> , D <sub>out</sub> = High-Z	
		—	1	—	1	—	1	—	1	—	1	mA	CMOS Interface RAS, CAS ≥ V <sub>CC</sub> - 0.2V D <sub>out</sub> = High-Z	
		—	300	—	300	—	300	—	300	—	300	μA	CMOS Interface L-Version	
Refresh Current	I <sub>CC3</sub>	—	90	—	80	—	60	—	50	—	45	mA	RAS Only Refresh, t <sub>RC</sub> = Min	2
Battery Back Up Current (Only for L-Version)	I <sub>CC4</sub>	—	300	—	300	—	300	—	300	—	300	μA	t <sub>RC</sub> = 125 μs, CAS Before RAS Cycling	4
Standby Current	I <sub>CC5</sub>	—	5	—	5	—	5	—	5	—	5	mA	RAS = V <sub>IH</sub> , CAS = V <sub>IL</sub> , D <sub>out</sub> = Enable	1
Refresh Current	I <sub>CC6</sub>	—	80	—	70	—	60	—	50	—	40	mA	CAS Before RAS Refresh t <sub>RC</sub> = Min	
Fast Page Mode Current	I <sub>CC7</sub>	—	80	—	70	—	50	—	50	—	40	mA	RAS = V <sub>IL</sub> , CAS Cycling, t <sub>PC</sub> = Min	1, 3



• DC Electrical Characteristics (V<sub>CC</sub> = 5V ± 10%, V<sub>SS</sub> = 0V, T<sub>A</sub> = 0 to +70°C) (continued)

Parameter	Symbol	HM511000A /AL-6		HM511000A /AL-7		HM511000 /A-8		HM511000 /A-10		HM511000 /A-12		Unit	Test Conditions	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max			
Input Leakage	I <sub>L1</sub>	-10	10	-10	10	-10	10	-10	10	-10	10	μA	V <sub>in</sub> = 0 to +7V	
Output Leakage	I <sub>L0</sub>	-10	10	-10	10	-10	10	-10	10	-10	10	μA	V <sub>out</sub> = 0 to +7V, D <sub>out</sub> = Disable	
Output Levels	V <sub>OH</sub>	2.4	V <sub>CC</sub>	2.4	V <sub>CC</sub>	2.4	V <sub>CC</sub>	2.4	V <sub>CC</sub>	2.4	V <sub>CC</sub>	V	I <sub>out</sub> = -5 mA	
	V <sub>OL</sub>	0	0.4	0	0.4	0	0.4	0	0.4	0	0.4	V	I <sub>out</sub> = 4.2 mA	

- Notes: 1. I<sub>CC</sub> depends on output loading condition when the device is selected. I<sub>CC</sub> max is specified at the output open condition.  
 2. Address can be changed less than three times while RAS = V<sub>IL</sub>.  
 3. Address can be changed once while CAS = V<sub>IH</sub>.  
 4. t<sub>RAS</sub> = t<sub>RAS</sub> (min) to 1 μs  
 Input voltage: All pins: V<sub>IH</sub> ≥ V<sub>CC</sub> - 0.2V or V<sub>IL</sub> ≤ 0.2V.

• Capacitance (V<sub>CC</sub> = 5V ± 10%, T<sub>A</sub> = 25°C)

Parameter	Symbol	Typ	Max	Unit	Note	
Input Capacitance	Address, Data Input	C <sub>I1</sub>	—	5	pF	1
	Clocks	C <sub>I2</sub>	—	7	pF	1
Output Capacitance	Data Output	C <sub>O</sub>	—	7	pF	1, 2

- Notes: 1. Capacitance measured with Boonton Meter or effective capacitance measuring method.  
 2. CAS = V<sub>IH</sub> to disable D<sub>out</sub>.

• AC Characteristics (T<sub>A</sub> = 0 to +70°C, V<sub>SS</sub> = 0V, V<sub>CC</sub> = 5V ± 10%)

Test Conditions

- Input rise and fall times: 5 ns  
 Input timing reference levels: 0.8V, 2.4V (Including scope and jig)  
 Output load: 2 TTL Gate + C<sub>L</sub> (100 pF)

Read, Write, Read-Modify-Write and Refresh Cycles (Common Parameters)

Parameter	Symbol	HM511000A /AL-6		HM511000A /AL-7		HM511000A /AL-8		HM511000A /AL-10		HM511000A /AL-12		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Random Read or Write Cycle Time	t <sub>RC</sub>	120	—	130	—	160	—	190	—	220	—	ns	
RAS Precharge Time	t <sub>RP</sub>	50	—	50	—	70	—	80	—	90	—	ns	
RAS Pulse Width	t <sub>RAS</sub>	60	10000	70	10000	80	10000	100	10000	120	10000	ns	
CAS Pulse Width	t <sub>CAS</sub>	20	10000	20	10000	25	10000	25	10000	30	10000	ns	
Row Address Setup Time	t <sub>ASR</sub>	0	—	0	—	0	—	0	—	0	—	ns	
Row Address Hold Time	t <sub>RAH</sub>	10	—	10	—	12	—	15	—	15	—	ns	
Column Address Setup Time	t <sub>ASC</sub>	0	—	0	—	0	—	0	—	0	—	ns	
Column Address Hold Time	t <sub>CAH</sub>	15	—	15	—	20	—	20	—	25	—	ns	
RAS to CAS Delay Time	t <sub>RCD</sub>	20	40	20	50	22	55	25	75	25	90	ns	8
RAS to Column Address Delay Time	t <sub>RAD</sub>	15	30	15	35	17	40	20	55	20	65	ns	9
RAS Hold Time	t <sub>RSH</sub>	20	—	20	—	25	—	25	—	30	—	ns	
CAS Hold Time	t <sub>CSH</sub>	60	—	70	—	80	—	100	—	120	—	ns	
CAS to RAS Precharge Time	t <sub>CRP</sub>	10	—	10	—	10	—	10	—	10	—	ns	
Transition Time (Rise and Fall)	t <sub>T</sub>	3	50	3	50	3	50	3	50	3	50	ns	7
Refresh Period	t <sub>REF</sub>	—	8	—	8	—	8	—	8	—	8	ms	
Refresh Period (Only for L-Version)	t <sub>REF</sub>	—	64	—	64	—	64	—	64	—	64	ms	



**Read Cycle**

Parameter	Symbol	HM511000A /AL-6		HM511000A /AL-7		HM511000A /AL-8		HM511000A /AL-10		HM511000A /AL-12		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Access Time from $\overline{\text{RAS}}$	$t_{\text{RAC}}$	—	60	—	70	—	80	—	100	—	120	ns	2, 3
Access Time from $\overline{\text{CAS}}$	$t_{\text{CAC}}$	—	20	—	20	—	25	—	25	—	30	ns	3, 4
Access Time from Address	$t_{\text{AA}}$	—	30	—	35	—	40	—	45	—	55	ns	3, 5
Read Command Setup Time	$t_{\text{RCS}}$	0	—	0	—	0	—	0	—	0	—	ns	
Read Command Hold Time to $\overline{\text{CAS}}$	$t_{\text{RCH}}$	0	—	0	—	0	—	0	—	0	—	ns	
Read Command Hold Time to $\overline{\text{RAS}}$	$t_{\text{RRH}}$	10	—	10	—	10	—	10	—	10	—	ns	10
Column Address to $\overline{\text{RAS}}$ Lead Time	$t_{\text{RAL}}$	30	—	35	—	40	—	45	—	55	—	ns	
Output Buffer Turn-off Time	$t_{\text{OFF}}$	—	20	—	20	—	20	—	25	—	30	ns	6

**Write Cycle**

Parameter	Symbol	HM511000A /AL-6		HM511000A /AL-7		HM511000A /AL-8		HM511000A /AL-10		HM511000A /AL-12		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Write Command Setup Time	$t_{\text{WCS}}$	0	—	0	—	0	—	0	—	0	—	ns	10
Write Command Hold Time	$t_{\text{WCH}}$	15	—	15	—	20	—	20	—	25	—	ns	
Write Command Pulse Width	$t_{\text{WP}}$	10	—	10	—	15	—	15	—	20	—	ns	
Write Command to $\overline{\text{RAS}}$ Lead Time	$t_{\text{RWL}}$	20	—	20	—	25	—	25	—	30	—	ns	
Write Command to $\overline{\text{CAS}}$ Lead Time	$t_{\text{CWL}}$	20	—	20	—	25	—	25	—	30	—	ns	
Data-in Setup Time	$t_{\text{DS}}$	0	—	0	—	0	—	0	—	0	—	ns	11
Data-in Hold Time	$t_{\text{DH}}$	15	—	15	—	20	—	20	—	25	—	ns	11

**Read-Modify-Write Cycle**

Parameter	Symbol	HM511000A /AL-6		HM511000A /AL-7		HM511000A /AL-8		HM511000A /AL-10		HM511000A /AL-12		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Read-Write Cycle Time	$t_{\text{RWC}}$	145	—	155	—	190	—	220	—	255	—	ns	
$\overline{\text{RAS}}$ to $\overline{\text{WE}}$ Delay Time	$t_{\text{RWD}}$	60	—	70	—	80	—	100	—	120	—	ns	10
$\overline{\text{CAS}}$ to $\overline{\text{WE}}$ Delay Time	$t_{\text{CWD}}$	20	—	20	—	25	—	25	—	30	—	ns	10
Column Address to $\overline{\text{WE}}$ Delay Time	$t_{\text{AWD}}$	30	—	35	—	40	—	45	—	55	—	ns	10

**Refresh Cycle**

Parameter	Symbol	HM511000A /AL-6		HM511000A /AL-7		HM511000A /AL-8		HM511000A /AL-10		HM511000A /AL-12		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
$\overline{\text{CAS}}$ Setup Time (CAS Before $\overline{\text{RAS}}$ Refresh)	$t_{\text{CSR}}$	10	—	10	—	10	—	10	—	10	—	ns	
$\overline{\text{CAS}}$ Hold Time (CAS Before $\overline{\text{RAS}}$ Refresh)	$t_{\text{CHR}}$	15	—	15	—	20	—	20	—	25	—	ns	
$\overline{\text{RAS}}$ Precharge to $\overline{\text{CAS}}$ Hold Time	$t_{\text{RPC}}$	10	—	10	—	10	—	0	—	0	—	ns	



## Fast Page Mode Cycle

Parameter	Symbol	HM511000A /AL-6		HM511000A /AL-7		HM511000A /AL-8		HM511000A /AL-10		HM511000A /AL-12		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Fast Page Mode Cycle Time	$t_{PC}$	45	—	50	—	55	—	55	—	65	—	ns	
CAS Precharge Time	$t_{CP}$	10	—	10	—	10	—	10	—	15	—	ns	
Fast Page Mode $\overline{RAS}$ Pulse Width	$t_{RASC}$	—	100000	—	100000	—	100000	—	100000	—	100000	ns	13
Access Time from CAS Precharge	$t_{ACP}$	—	40	—	45	—	50	—	50	—	60	ns	14
$\overline{RAS}$ Hold Time from CAS Precharge	$t_{RHCP}$	40	—	45	—	50	—	50	—	60	—	ns	

## Fast Page Mode Read-Modify-Write Cycle

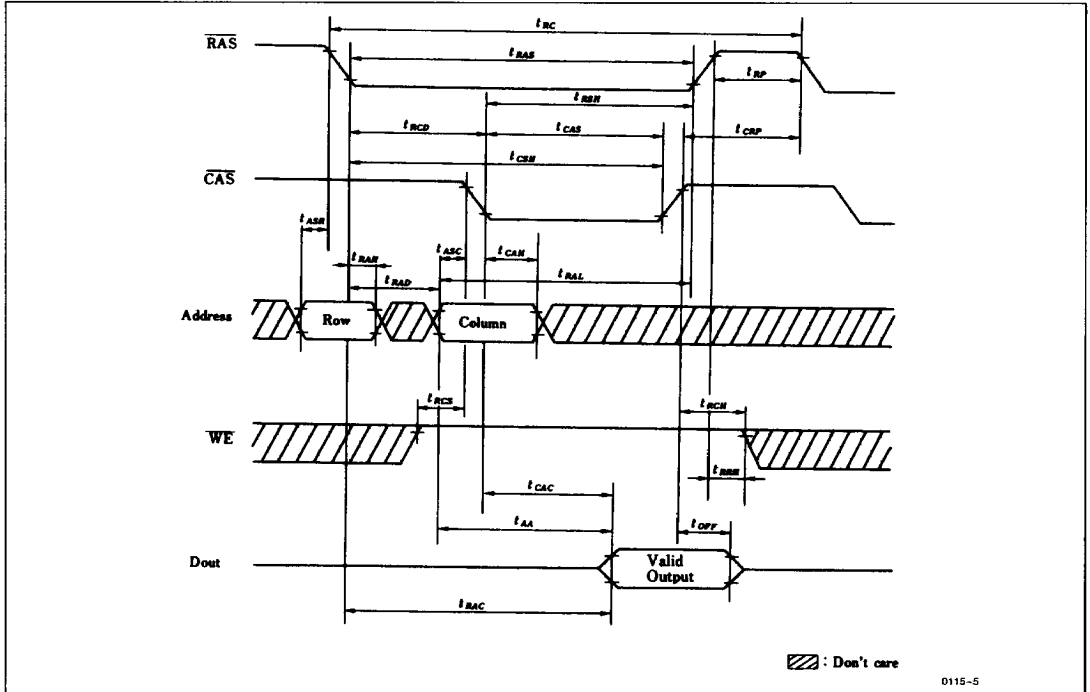
Parameter	Symbol	HM511000A /AL-6		HM511000A /AL-7		HM511000A /AL-8		HM511000A /AL-10		HM511000A /AL-12		Unit	Note
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max		
Fast Page Mode Read-Modify-Write Cycle Time	$t_{PCM}$	70	—	75	—	85	—	85	—	100	—	ns	

- Notes:
- AC measurements assume  $t_T = 5$  ns.
  - Assumes that  $t_{RCD} \leq t_{RCD}(\max)$  and  $t_{RAD} \leq t_{RAD}(\max)$ . If  $t_{RCD}$  or  $t_{RAD}$  is greater than the maximum recommended value shown in this table,  $t_{RAC}$  exceeds the value shown.
  - Measured with a load circuit equivalent to 2 TTL loads and 100 pF.
  - Assumes that  $t_{RCD} \geq t_{RCD}(\max)$ ,  $t_{RAD} \leq t_{RAD}(\max)$ .
  - Assumes that  $t_{RCD} \leq t_{RCD}(\max)$ , and  $t_{RAD} \geq t_{RAD}(\max)$ .
  - $t_{OFF}(\max)$  is defined as the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.
  - Transition times are measured between  $V_{IH}$  and  $V_{IL}$ .
  - Operation with the  $t_{RCD}(\max)$  limit insures that  $t_{RAC}(\max)$  can be met,  $t_{RCD}(\max)$  is specified as a reference point only, if  $t_{RCD}$  is greater than the specified  $t_{RCD}(\max)$  limit, then access time is controlled exclusively by  $t_{CAC}$ .
  - Operation with the  $t_{RAD}(\max)$  limit insures that  $t_{RAC}(\max)$  can be met,  $t_{RAD}(\max)$  is specified as a reference point only, if  $t_{RAD}$  is greater than the specified  $t_{RAD}(\max)$  limit, then access time is controlled exclusively by  $t_{AA}$ .
  - $t_{WCS}$ ,  $t_{RWD}$ ,  $t_{CWD}$  and  $t_{AWD}$  are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only: if  $t_{WCS} \geq t_{WCS}(\min)$ , the cycle is an early write cycle and the data out pin will remain open circuit (high impedance) throughout the entire cycle; if  $t_{RWD} \geq t_{RWD}(\min)$ ,  $t_{CWD} \geq t_{CWD}(\min)$  and  $t_{AWD} \geq t_{AWD}(\min)$ , the cycle is a read/write and the data output will contain data read from the selected cell; if neither of the above sets of conditions is satisfied, the condition of the data out (at access time) is indeterminate.
  - These parameters are referenced to  $\overline{CAS}$  leading edge in early write cycles and to  $\overline{WE}$  leading edge in delayed write or read-modify-write cycles.
  - An initial pause of 100  $\mu$ s is required after power-up followed by eight or more initialization cycles (any combination of cycles containing  $\overline{RAS}$  clock such as  $\overline{RAS}$  only refresh). If internal refresh counter is used, eight or more CAS before  $\overline{RAS}$  refresh cycles are required.
  - $t_{RASC}$  is determined by  $\overline{RAS}$  pulse width in fast page mode cycle.
  - Access time is determined by the longer of  $t_{AA}$ ,  $t_{CAC}$  or  $t_{ACP}$ .

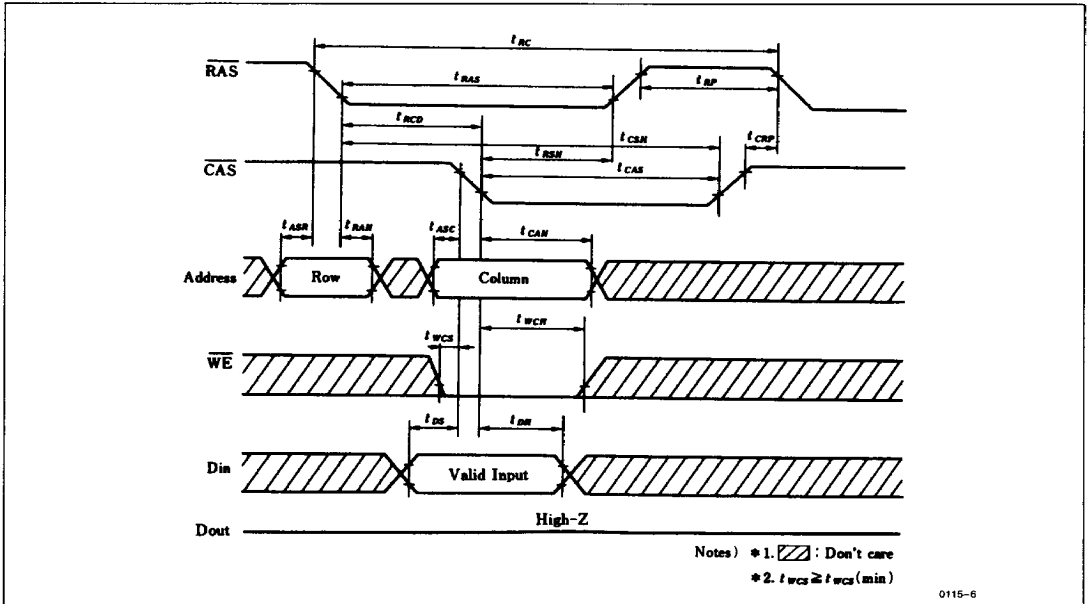


■ TIMING WAVEFORMS

• Read Cycle

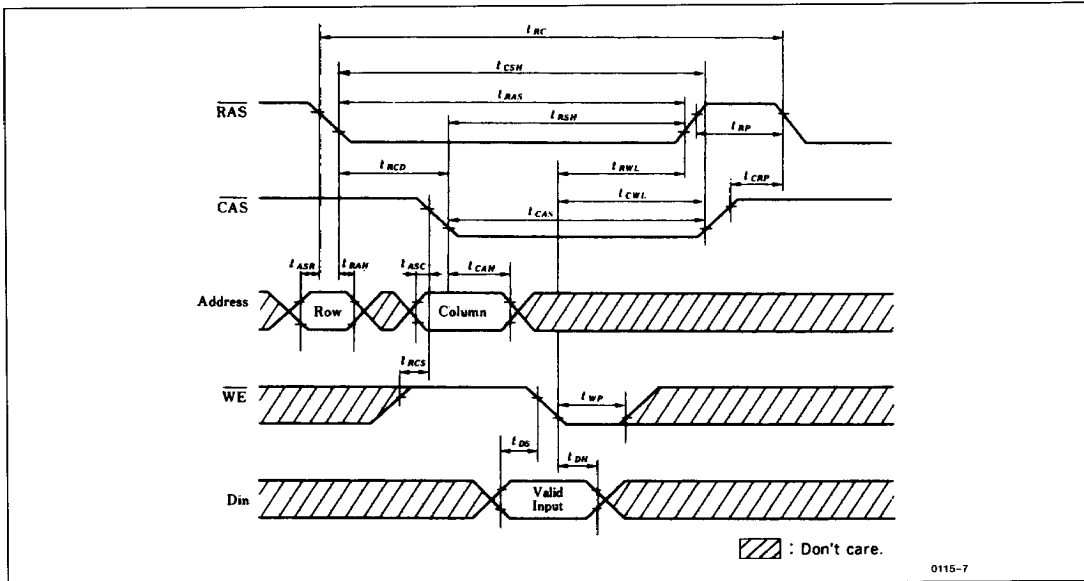


• Early Write Cycle

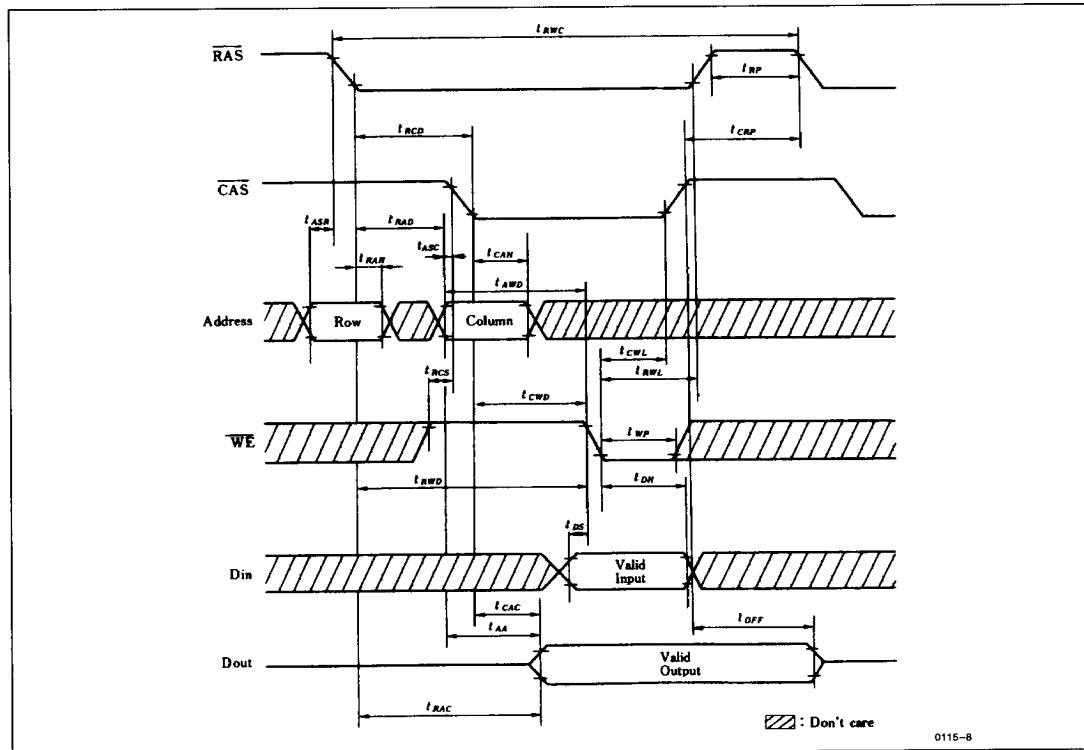




• Delayed Write Cycle



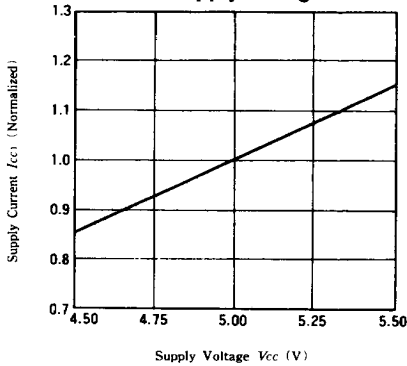
• Read-Modify-Write Cycle



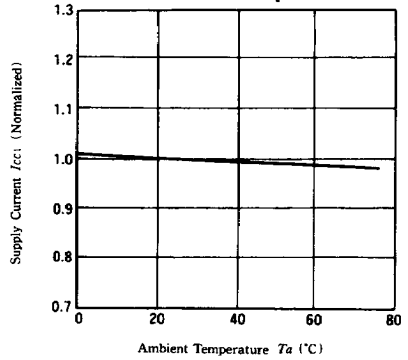




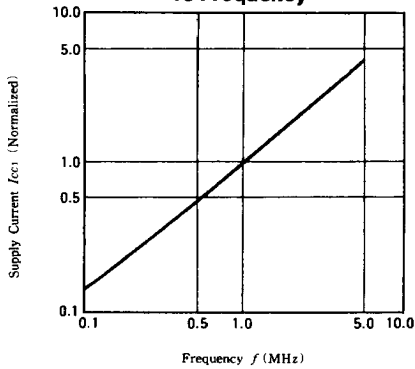
**Supply Current (Active)  
vs Supply Voltage**



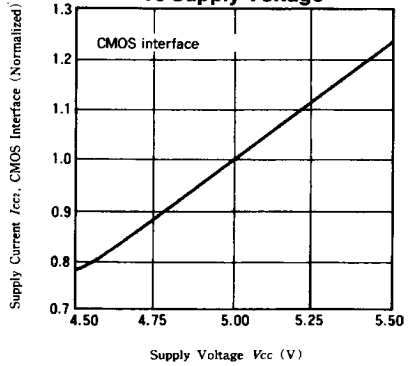
**Supply Current (Active)  
vs Ambient Temperature**



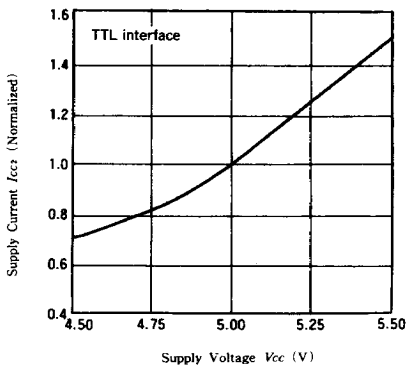
**Supply Current (Active)  
vs Frequency**



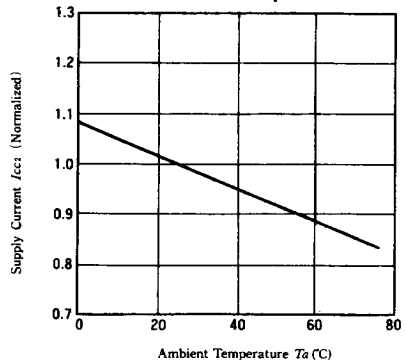
**Supply Current (Standby)  
vs Supply Voltage**



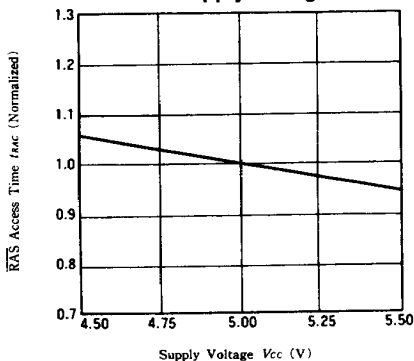
**Supply Current (Standby)  
vs Supply Voltage**



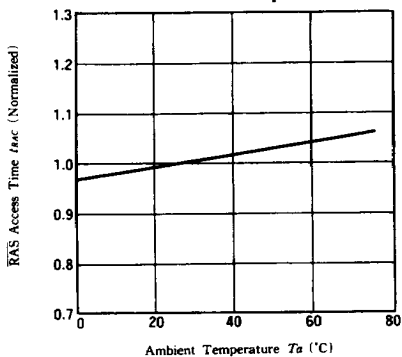
**Supply Current (Standby)  
vs Ambient Temperature**



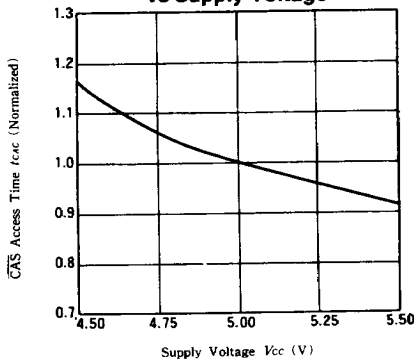
**RAS Access Time vs Supply Voltage**



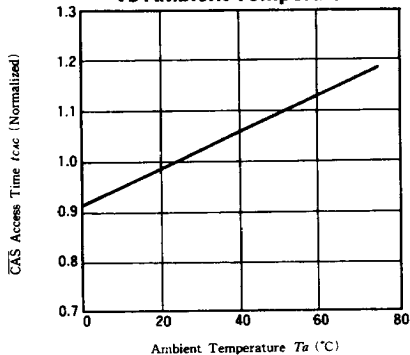
**RAS Access Time vs Ambient Temperature**



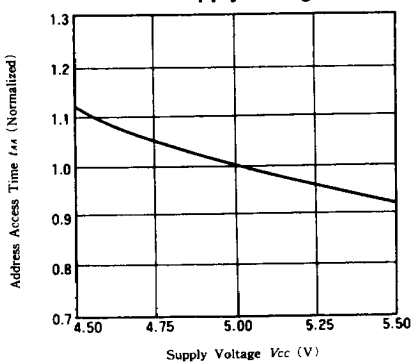
**CAS Access Time vs Supply Voltage**



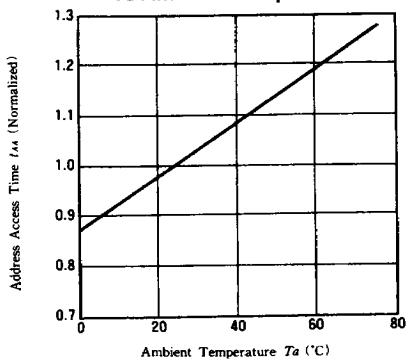
**CAS Access Time vs Ambient Temperature**



**Address Access Time vs Supply Voltage**



**Address Access Time vs Ambient Temperature**



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